

July, 2007

# FGA25N120ANTD/FGA25N120ANTD\_F109 1200V NPT Trench IGBT

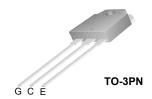
#### **Features**

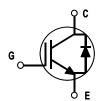
- · NPT Trench Technology, Positive temperature coefficient
- Low saturation voltage: V<sub>CE(sat), typ</sub> = 2.0V
   Q I<sub>C</sub> = 25A and T<sub>C</sub> = 25°C
- Low switching loss:  $E_{\rm off,\ typ}$  = 0.96mJ @ I<sub>C</sub> = 25A and T<sub>C</sub> = 25°C
- · Extremely enhanced avalanche capability

### **Description**

Using Fairchild's proprietary trench design and advanced NPT technology, the 1200V NPT IGBT offers superior conduction and switching performances, high avalanche ruggedness and easy parallel operation.

This device is well suited for the resonant or soft switching application such as induction heating, microwave oven, etc.





### **Absolute Maximum Ratings**

Symbol	Description		FGA25N120ANTD	Units
V <sub>CES</sub>	Collector-Emitter Voltage		1200	V
V <sub>GES</sub>	Gate-Emitter Voltage		± 20	V
I <sub>C</sub>	Collector Current	@ T <sub>C</sub> = 25°C	50	Α
	Collector Current	@ T <sub>C</sub> = 100°C	25	Α
I <sub>CM</sub>	Pulsed Collector Current (Note 1)		90	А
I <sub>F</sub>	Diode Continuous Forward Current @ T <sub>C</sub> = 100°C		25	А
I <sub>FM</sub>	Diode Maximum Forward Current		150	А
$P_{D}$	Maximum Power Dissipation	@ T <sub>C</sub> = 25°C	312	W
	Maximum Power Dissipation	@ T <sub>C</sub> = 100°C	125	W
T <sub>J</sub>	Operating Junction Temperature		-55 to +150	°C
T <sub>stg</sub>	Storage Temperature Range		-55 to +150	°C
T <sub>L</sub>	Maximum Lead Temp. for soldering Purposes, 1/8" from case for 5 seconds		300	°C

#### **Thermal Characteristics**

Symbol	Parameter	Тур.	Max.	Units
$R_{ heta JC}$	Thermal Resistance, Junction-to-Case for IGBT		0.4	°C/W
$R_{ heta JC}$	Thermal Resistance, Junction-to-Case for Diode		2.0	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		40	°C/W

## **Package Marking and Ordering Information**

Device Marking Device		Package	Reel Size	Tape Width	Quantity	
FGA25N120ANTD FGA25N120ANTD		TO-3P	-	-	30	

## Electrical Characteristics of the IGBT $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
Off Charac	eteristics					
I <sub>CES</sub>	Collector Cut-Off Current	$V_{CE} = V_{CES}, V_{GE} = 0V$			3	mA
I <sub>GES</sub>	G-E Leakage Current	$V_{GE} = V_{GES}, V_{CE} = 0V$			± 250	nA
On Charac	teristics					
V <sub>GE(th)</sub>	G-E Threshold Voltage	$I_C$ = 25mA, $V_{CE}$ = $V_{GE}$	3.5	5.5	7.5	V
V <sub>CE(sat)</sub>	Collector to Emitter	I <sub>C</sub> = 25A, V <sub>GE</sub> = 15V		2.0	2.5	V
. (,	Saturation Voltage	I <sub>C</sub> = 25A, V <sub>GE</sub> = 15V, T <sub>C</sub> = 125°C		2.15		٧
		I <sub>C</sub> = 50A, V <sub>GE</sub> = 15V		2.65		V
D	No		•	•	•	
C <sub>ies</sub>	Characteristics Input Capacitance	V <sub>CE</sub> = 30V, V <sub>GE</sub> = 0V,		3700		pF
C <sub>oes</sub>	Output Capacitance	f = 1MHz		130		рF
C <sub>res</sub>	Reverse Transfer Capacitance			80		pF
Switching t <sub>d(on)</sub>	Characteristics Turn-On Delay Time	V <sub>CC</sub> = 600 V, I <sub>C</sub> = 25A,		50		ns
$t_{d(on)}$	Turn-On Delay Time	$V_{CC} = 600 \text{ V, } I_{C} = 25\text{A,}$ $R_{G} = 10\Omega, V_{GE} = 15\text{V,}$		50		ns
t <sub>r</sub>	Rise Time	Inductive Load, $T_C = 25^{\circ}C$		60	90	ns
t <sub>d(off)</sub>	Turn-Off Delay Time			190		ns
t <sub>f</sub>	Fall Time			100	180	ns
E <sub>on</sub>	Turn-On Switching Loss			4.1	6.2	mJ
E <sub>off</sub>	Turn-Off Switching Loss			0.96	1.5	mJ
E <sub>ts</sub>	Total Switching Loss			5.06	7.7	mJ
$t_{d(on)}$	Turn-On Delay Time	$V_{CC} = 600 \text{ V}, I_{C} = 25\text{A},$		50		ns
t <sub>r</sub>	Rise Time	$R_G = 10\Omega$ , $V_{GE} = 15V$ , Inductive Load, $T_C = 125^{\circ}C$		60		ns
$t_{d(off)}$	Turn-Off Delay Time	illuuctive Load, I <sub>C</sub> = 125 <sup>-</sup> C		200		ns
t <sub>f</sub>	Fall Time			154		ns
E <sub>on</sub>	Turn-On Switching Loss			4.3	6.9	mJ
E <sub>off</sub>	Turn-Off Switching Loss			1.5	2.4	mJ
E <sub>ts</sub>	Total Switching Loss			5.8	9.3	mJ
Qg	Total Gate Charge	V <sub>CE</sub> = 600 V, I <sub>C</sub> = 25A,		200	300	nC
Q <sub>ge</sub>	Gate-Emitter Charge	V <sub>GE</sub> = 15V		15	23	nC
Q <sub>gc</sub>				100	1	nC

#### Notes

(1) Repetitive rating: Pulse width limited by  $\max$  junction temperature

## Electrical Characteristics of DIODE $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Test Conditions		Min.	Тур.	Max.	Units
$V_{FM}$	Diode Forward Voltage	I <sub>F</sub> = 25A	T <sub>C</sub> = 25°C		2.0	3.0	V
			T <sub>C</sub> = 125°C		2.1		
t <sub>rr</sub>	Diode Reverse Recovery Time	I <sub>F</sub> = 25A	T <sub>C</sub> = 25°C		235	350	ns
		dI/dt = 200 A/μs	T <sub>C</sub> = 125°C		300		
I <sub>rr</sub>	Diode Peak Reverse Recovery Cur-		T <sub>C</sub> = 25°C		27	40	Α
	rent		T <sub>C</sub> = 125°C		31		
Q <sub>rr</sub>	Diode Reverse Recovery Charge		T <sub>C</sub> = 25°C		3130	4700	nC
			T <sub>C</sub> = 125°C		4650		

## **Typical Performance Characteristics**

Figure 1. Typical Output Characteristics

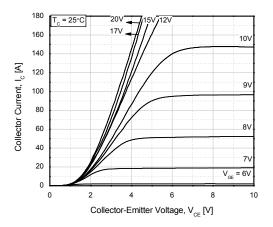


Figure 3. Saturation Voltage vs. Case
Temperature at Variant Current Level

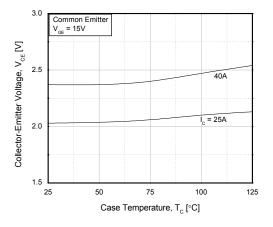


Figure 5. Saturation Voltage vs. V<sub>GE</sub>

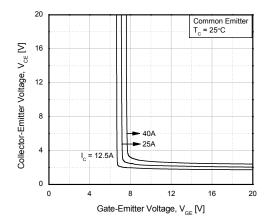


Figure 2. Typical Saturation Voltage Characteristics

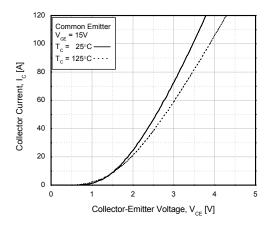


Figure 4. Saturation Voltage vs. V<sub>GE</sub>

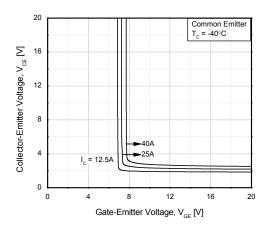
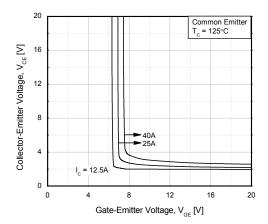


Figure 6. Saturation Voltage vs. V<sub>GE</sub>



### Typical Performance Characteristics (Continued)

Figure 7. Capacitance Characteristics

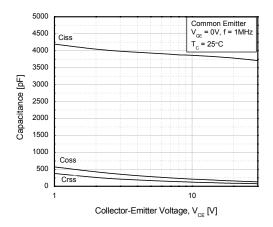


Figure 9. Turn-Off Characteristics vs.
Gate Resistance

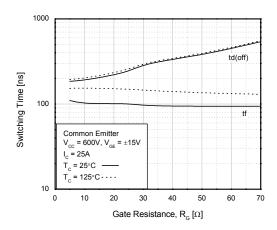


Figure 11. Turn-On Characteristics vs. Collector Current

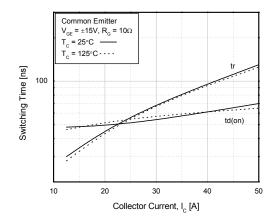


Figure 8. Turn-On Characteristics vs. Gate Resistance

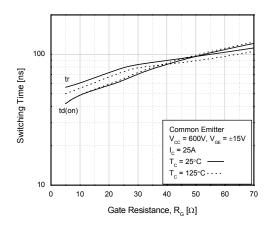


Figure 10. Switching Loss vs. Gate Resistance

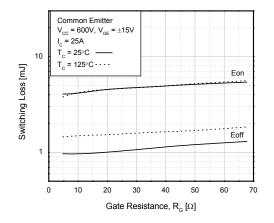
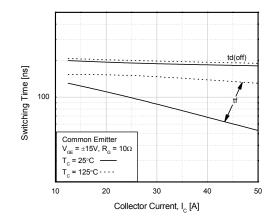
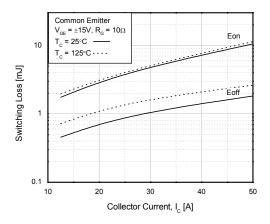


Figure 12. Turn-Off Characteristics vs. Collector Current



### Typical Performance Characteristics (Continued)

Figure 13. Switching Loss vs. Collector Current



**Figure 14. Gate Charge Characteristics** 

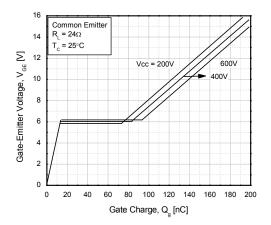


Figure 15. SOA Characteristics

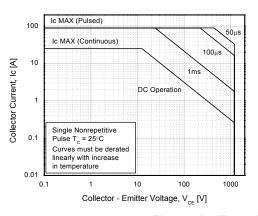


Figure 16. Turn-Off SOA

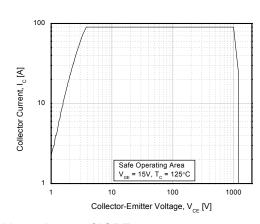
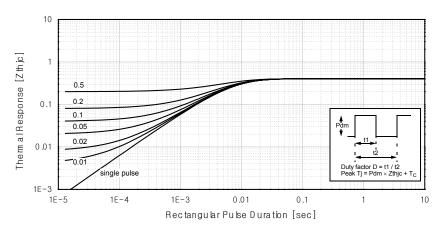


Figure 17. Transient Thermal Impedance of IGBT



# Typical Performance Characteristics (Continued)

#### Figure 18. Forward Characteristics

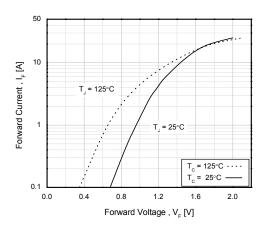
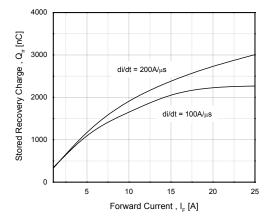


Figure 20. Stored Charge



**Figure 19. Reverse Recovery Current** 

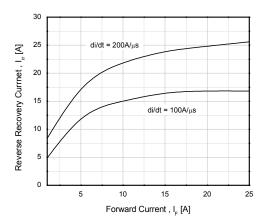
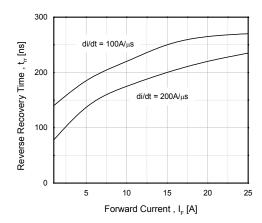
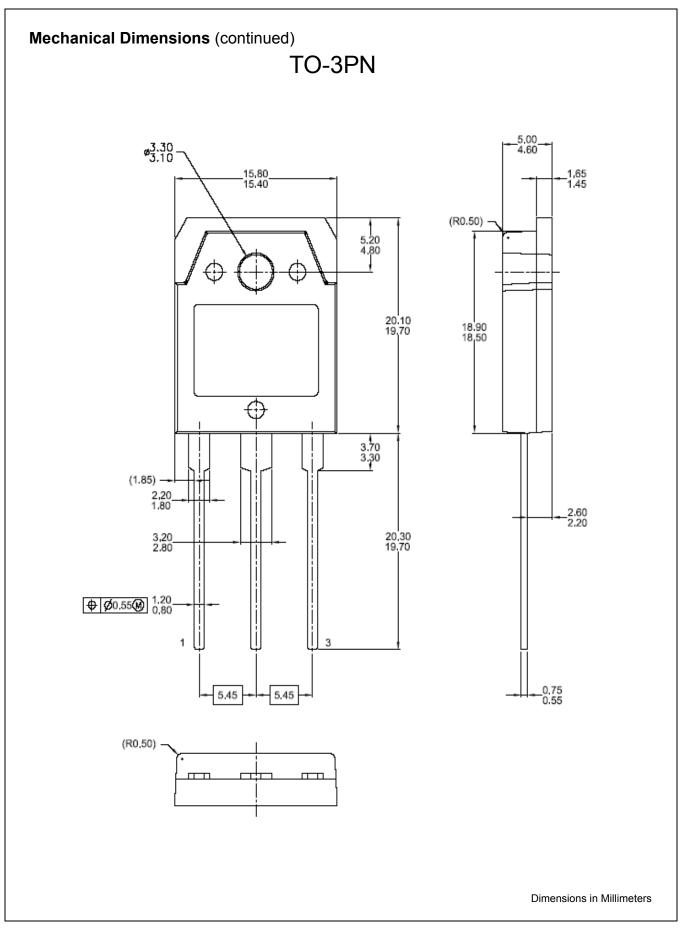


Figure 21. Reverse Recovery Time





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